Application/Control No. Applicant(s)/Patent Under Reexamination 10/067,304 FUJII ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Ba Huynh 2179 **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-2002/0071540 Α 06-2002 Dworkin, David S. 379/202.01 В US-С US-US-D Ε US-F US-G US-Н US-US-US-J K US-L US-US-FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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